

Docket No.: 65326-029

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

Yasushi SASA, et al.

Serial No.: 10/657,107

Filed: September 09, 2003

For: DEFECT INSPECTION APPARATUS, DEFECT INSPECTION METHOD AND  
PROGRAM



: Customer Number: 20277  
:  
: Confirmation Number: 9832  
:  
: Group Art Unit: 2621  
:  
: Examiner: not yet assigned  
:

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

To ensure that the referenced are available to the Examiner we are providing copies.

10/657,107

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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**Date: December 16, 2003**

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

 ATTY. DOCKET NO.  
**65326-029**

 SERIAL NO.  
**10/657,107**

 APPLICANT  
**Yasushi SASA, et al.**

 FILING DATE  
**September 09, 2003**

 GROUP  
**2621**

(PTO-1449)

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	B1	US 6,169,282	01/02/2001	Maeda et al.	
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 2002-022421	01/23/2002	Dainippon Screen Mfg. Co., Ltd.		X	
		JP 11-132959 with U.S. Counterpart listed above	05/21/1999				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Nobuyuki Otsu "An Automatic Threshold Selection Method Based on Discriminant and Least Squares Criteria" IEICE, '80/4 vol. J63-D, No. 4, pp. 349-356 (with English translation of the abstract)
		Nobuyuki Otsu "A Threshold Selection Method from Gray-Level Histograms" IEEE Transactions on Systems, Man, and Cybernetics, 79/1 vol. SMC-9, No. 1, pp. 62-66

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.